

1. General description

Ultrafast power diode (Bare die after sawn).

2. Features and benefits

- Low Forward Voltage Drop
- Low leakage current
- Fast reverse recovery
- Bare die

3. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V_{RRM}^*	repetitive peak reverse voltage			-	-	1200	V
$I_{F(AV)}^{**}$	average forward current	$\delta = 0.5$; square-wave pulse		-	-	5	A
Static characteristics							
V_F^{**}	forward voltage	$I_F = 5\text{ A}$; $T_J = 25\text{ °C}$		-	1.7	2.2	V
Dynamic characteristics							
t_{rr}^{**}	reverse recovery time	$I_F = 1\text{ A}$; $V_R = 30\text{ V}$; $di_F/dt = 100\text{ A}/\mu\text{s}$; $T_J = 25\text{ °C}$		-	50	-	ns

4. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
WNB087R5APPS12	Wafer	Bare die on wafer	Die

5. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{RRM}^*	repetitive peak reverse voltage			-	1200	V
V_{RWM}^*	crest working reverse voltage			-	1200	V
V_R^*	reverse voltage	DC		-	1200	V
$I_{F(AV)}^{**}$	average forward current	$\delta = 0.5$; square-wave pulse		-	5	A
I_{FRM}^{**}	repetitive peak forward current	$\delta = 0.5$; $t_p = 25 \mu s$; square-wave pulse		-	10	A
I_{FSM}^{**}	non-repetitive peak forward current	$t_p = 10 \text{ ms}$; $T_{j(\text{init})} = 25 \text{ }^\circ\text{C}$; sine-wave pulse		-	55	A
		$t_p = 8.3 \text{ ms}$; $T_{j(\text{init})} = 25 \text{ }^\circ\text{C}$; sine-wave pulse		-	60	A
T_{stg}^{**}	storage temperature			-65	175	$^\circ\text{C}$
T_j^{**}	junction temperature				175	$^\circ\text{C}$

6. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
V_F^*	forward voltage	$I_F = 5\text{ A}; T_J = 25\text{ °C}$		-	1.7	2.2	V
V_F^{**}	forward voltage	$I_F = 5\text{ A}; T_J = 150\text{ °C}$		-	1.55	-	V
I_R^*	reverse current	$V_R = 1200\text{ V}; T_J = 25\text{ °C}$		-	-	50	μA
I_R^{**}	reverse current	$V_R = 1200\text{ V}; T_J = 150\text{ °C}$		-	-	500	μA
Dynamic characteristics							
t_{rr}^{**}	reverse recovery time	$I_F = 1\text{ A}; V_R = 30\text{ V}; dI_F/dt = 100\text{ A}/\mu\text{s}; T_J = 25\text{ °C}$		-	50	-	ns
		$I_F = 5\text{ A}; V_R = 400\text{ V}; dI_F/dt = 500\text{ A}/\mu\text{s}; T_J = 25\text{ °C}$		-	62	-	ns
		$I_F = 5\text{ A}; V_R = 400\text{ V}; dI_F/dt = 500\text{ A}/\mu\text{s}; T_J = 125\text{ °C}$		-	85	-	ns
		$I_F = 5\text{ A}; V_R = 400\text{ V}; dI_F/dt = 500\text{ A}/\mu\text{s}; T_J = 150\text{ °C}$		-	90	-	ns

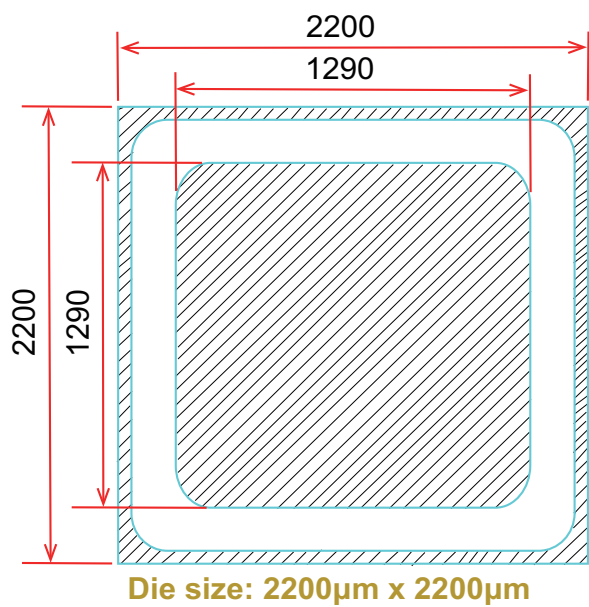
Notes:

(1) * mean that parameter are 100% test at $T_{amb} = 25\text{ °C}$

(2) ** means that the guaranteed ratings and parameter limits will depend on the assembled structure. When correctly assembled with suitable die bonding and wire bonding, the device will have ratings and characteristics guaranteed in this data sheet, similar to the assembled devices BYR5D-1200P.

MECHANICAL PATAMETER		
Chip size	2.2 x 2.2	mm ²
Anode pad size	1.29 x 1.29	mm ²
Area total / active	4.84 / 1.66	mm ²
Thickness	300	μm
Wafer size	125	mm
Max possible chips per wafer	2229	pcs
Passivation	P.E.C.V.D./ Planar	
Front metal	Al	
Back metal	Ti Ni Ag	

CHIP LAYOUT



7. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions".
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8. Contents

1. General description..... 1

2. Features and benefits 1

3. Quick reference data 1

4. Ordering information..... 1

5. Limiting values 2

6. Characteristics..... 3

7. Legal information 5

8. Contents 7

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Date of release: 14 December 2018